

OptiMOS[™]3 Power-Transistor

Features

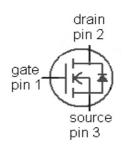
- for sync. rectification, drives and dc/dc SMPS
- Excellent gate charge x R DS(on) product (FOM)
- Very low on-resistance R_{DS(on)}
- N-channel, normal level
- Avalanche rated
- Qualified according to JEDEC¹⁾ for target applications
- Pb-free plating; RoHS compliant
- · Halogen-free according to IEC61249-2-21

Туре	IPB090N06N3 G	IPP093N06N3 G
	1 3 2 (tab)	123
Package	PG-TO263-3	PG-TO220-3
Marking	090N06N	093N06N

Product Summary

V _{DS}	60	٧
R _{DS(on),max (SMD)}	9	mΩ
I _D	50	А





Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	I _D	T _C =25 °C ²⁾	50	А
		T _C =100 °C	50	
Pulsed drain current ³⁾	I _{D,pulse}	T _C =25 °C	200	
Avalanche energy, single pulse	E _{AS}	$I_{\rm D}$ =50 A, $R_{\rm GS}$ =25 Ω	43	mJ
Gate source voltage	V_{GS}		±20	V
Power dissipation	P_{tot}	T _C =25 °C	71	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

¹⁾J-STD20 and JESD22

 $^{^{2)}}$ Current is limited by bondwire; with an $R_{\rm thJC}$ =1.6 K/W the chip is able to carry 74 A.

³⁾ See figure 3

 $^{^{4)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



IPB090N06N3 G IPP093N06N3 G

Parameter	Symbol	Conditions	Values		Unit	
			min.	typ.	max.	<u>] </u>
Thermal characteristics						
Thermal resistance, junction - case	R_{thJC}		-	-	1.6	K/W
Thermal resistance,	R_{thJA}	minimal footprint	-	-	62	1
junction - ambient		6 cm² cooling area ⁴⁾	-	-	40]

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	V _{GS} =0 V, I _D =1 mA	60	-	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS}=V_{\rm GS}, I_{\rm D}=34~\mu{\rm A}$	2	3	4	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS}$ =60 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	1	0.1	1	μΑ
		V _{DS} =60 V, V _{GS} =0 V, T _j =125 °C	1	10	100	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	1	1	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10 V, I _D =50 A	1	8.0	9.3	mΩ
		V _{GS} =10 V, I _D =50 A, (SMD)	1	7.7	9	
Gate resistance	R_{G}		1	0.7	-	Ω
Transconductance	g_{fs}	V _{DS} >2 I _D R _{DS(on)max} , I _D =50 A	28	55	-	s



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Parameter	Symbol	Symbol Conditions		Values		Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	Ciss		-	2900	-	pF
Output capacitance	Coss	V _{GS} =0 V, V _{DS} =30 V, f=1 MHz	-	640	-	1
Reverse transfer capacitance	C _{rss}]	-	23	-	1
Turn-on delay time	$t_{d(on)}$		-	15	-	ns
Rise time	t _r	V _{DD} =30 V, V _{GS} =10 V,	-	40	-	1
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =45 A, $R_{\rm G}$ =3.5 Ω	-	20	-	
Fall time	t_{f}]	-	5	-	
Gate Charge Characteristics ⁵⁾	_			,		_
Gate to source charge	Q _{gs}		-	16	-	nC
Gate to drain charge	Q_{gd}		-	3	-	
Switching charge	Q _{sw}	V_{DD} =30 V, I_{D} =50 A, V_{GS} =0 to 10 V	-	11	-	
Gate charge total	Qg		ı	36	-	
Gate plateau voltage	V _{plateau}		-	5.6	-	V
Output charge	Q _{oss}	V _{DD} =30 V, V _{GS} =0 V	-	29	-	nC
Reverse Diode	•					
Diode continous forward current	Is	T -25 °C	-	-	50	А
Diode pulse current	I _{S,pulse}	T _C =25 °C	-	-	200	1
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =50 A, T _j =25 °C	-	1.0	1.2	V
Reverse recovery time	t _{rr}	V _R =30 V, I _F =45A,	-	45		ns
Reverse recovery charge	Q _{rr}	d <i>i_F</i> /d <i>t</i> =100 A/μs	-	40	-	nC

⁵⁾ See figure 16 for gate charge parameter definition

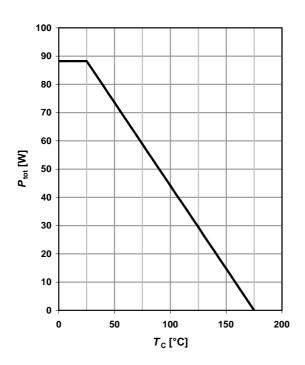


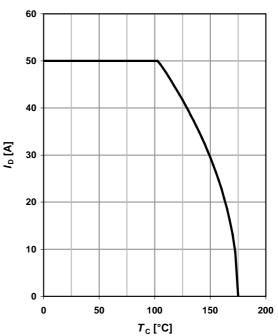
1 Power dissipation

P_{tot} =f(T_{C})

2 Drain current

$$I_D = f(T_C); V_{GS} \ge 10 \text{ V}$$





3 Safe operating area

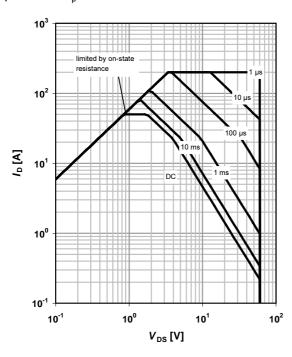
$$I_D$$
=f(V_{DS}); T_C =25 °C; D =0

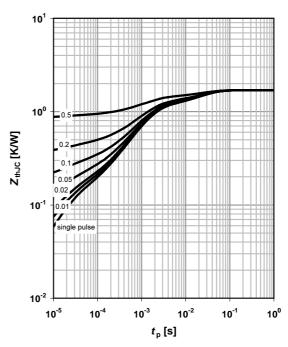
parameter: t_p

4 Max. transient thermal impedance

$$Z_{\rm thJC}$$
=f($t_{\rm p}$)

parameter: $D=t_p/T$



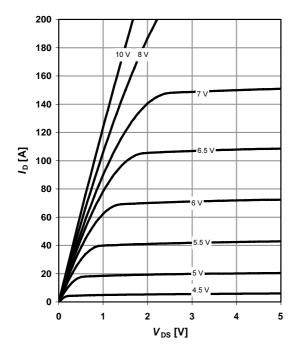




5 Typ. output characteristics

 $I_D=f(V_{DS}); T_j=25 \text{ °C}$

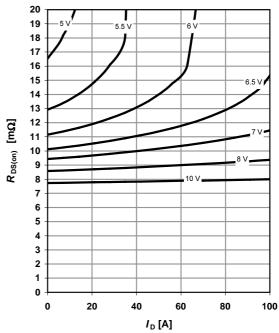
parameter: $V_{\rm GS}$



6 Typ. drain-source on resistance

 $R_{DS(on)}$ =f(I_D); T_j =25 °C

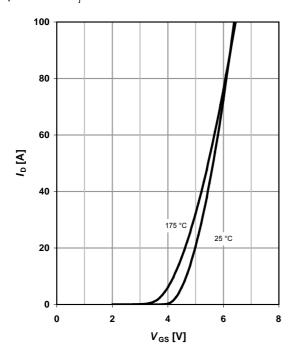
parameter: V_{GS}



7 Typ. transfer characteristics

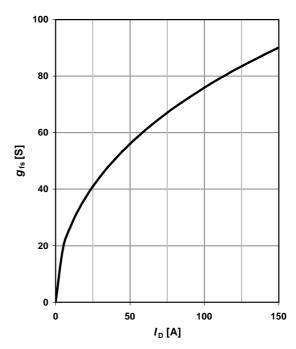
 I_{D} =f(V_{GS}); $|V_{DS}|$ >2 $|I_{D}|R_{DS(on)max}$

parameter: T_j



8 Typ. forward transconductance

 g_{fs} =f(I_D); T_j =25 °C





9 Drain-source on-state resistance

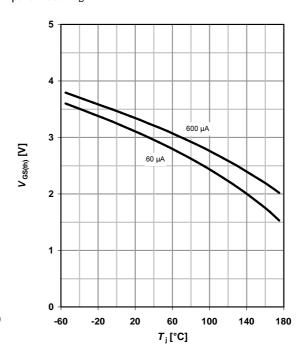
 $R_{DS(on)} = f(T_j); I_D = 50 \text{ A}; V_{GS} = 10 \text{ V}$

20 18 16 14 $R_{\rm DS(on)}$ [m Ω] 12 10 6 4 2 0 -60 -20 20 60 140 180

*T*_j [°C]

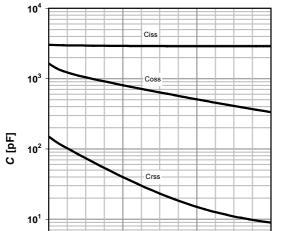
10 Typ. gate threshold voltage

 $V_{\text{GS(th)}}$ =f(T_{j}); V_{GS} = V_{DS} parameter: I_{D}



11 Typ. capacitances

 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$

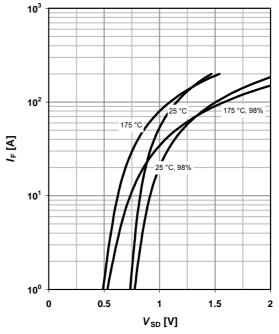


20

 $V_{\rm DS}\,[{
m V}]$

12 Forward characteristics of reverse diode

 $I_{\text{F}} = f(V_{\text{SD}})$ parameter: T_{j}



60



13 Avalanche characteristics

 I_{AS} =f(t_{AV}); R_{GS} =25 Ω

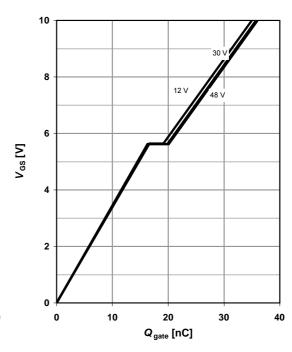
parameter: $T_{j(start)}$

100 150 °C 100 °C 25 °C 25 °C 100 °C 25 °C 100 °C 25 °C 100 °C 25 °C 100 °C 100 °C 100 °C 1000 °C 10

14 Typ. gate charge

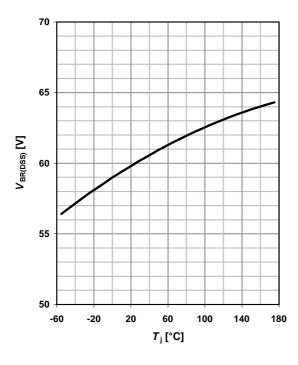
 $V_{\rm GS}$ =f(Q_{gate}); $I_{\rm D}$ =50 A pulsed

parameter: $V_{\rm DD}$

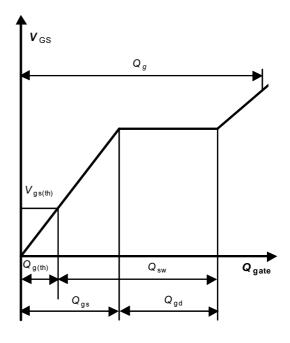


15 Drain-source breakdown voltage

 $V_{BR(DSS)}$ =f(T_j); I_D =1 mA

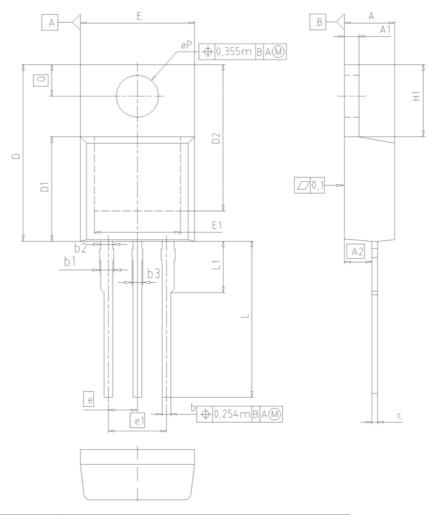


16 Gate charge waveforms

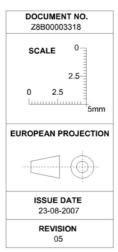




PG-TO220-3

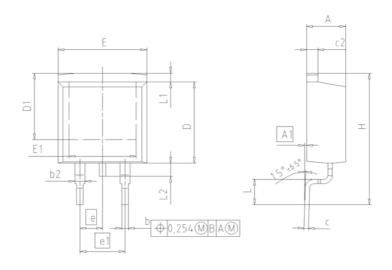


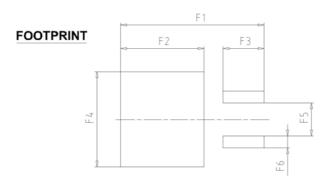
DIM	MILLI	METERS	INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	4.30	4.57	0.169	0.180	
A1	1.17	1.40	0.046	0.055	
A2	2.15	2.72	0.085	0.107	
b	0.65	0.86	0.026	0.034	
b1	0.95	1.40	0.037	0.055	
b2	0.95	1.15	0.037	0.045	
b3	0.65	1.15	0.026	0.045	
С	0.33	0.60	0.013	0.024	
D	14.81	15.95	0.583	0.628	
D1	8.51	9.45	0.335	0.372	
D2	12.19	13.10	0.480	0.516	
E	9.70	10.36	0.382	0.408	
E1	6.50	8.60	0.256	0.339	
е	2	2.54	0.1	00	
e1	5.08		0.2	00	
N		3	:	3	
H1	5.90	6.90	0.232	0.272	
L	13.00	14.00	0.512	0.551	
L1	-	4.80	-	0.189	
øΡ	3.60	3.89	0.142	0.153	
Q	2.60	3.00	0.102	0.118	



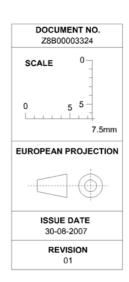


PG-TO263 (D2-Pak)





DIM	MILLIM	ETERS	INCHES			
DIM	MIN	MAX	MIN	MAX		
Α	4.30	4.57	0.169	0.180		
A1	0.00	0.25	0.000	0.010		
b	0.65	0.85	0.026	0.033		
b2	0.95	1.15	0.037	0.045		
С	0.33	0.65	0.013	0.026		
c2	1.17	1.40	0.046	0.055		
D	8.51	9.45	0.335	0.372		
D1	7.10	7.90	0.280	0.311		
E	9.80	10.31	0.386	0.406		
E1	6.50	8.60	0.256	0.339		
е	2.5	54	0.1	0.100		
e1	5.0	5.08		0.200		
N		2	2			
н	14.61	15.88	0.575	0.625		
L	2.29	3.00	0.090	0.118		
L1	0.70	1.60	0.028	0.063		
L2	1.00	1.78	0.039	0.070		
F1	16.05	16.25	0.632	0.640		
F2	9.30	9.50	0.366	0.374		
F3	4.50	4.70	0.177	0.185		
F4	10.70	10.90	0.421	0.429		
F5	3.65	3.85	0.144	0.152		
F6	1.25	1.45	0.049	0.057		





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Infineon Technologies AG
81726 Munich, Germany
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